


Search Notes 	Application/Control No. 10551671	Applicant(s)/Patent Under Reexamination ADAMEK ET AL.
	Examiner SHEELA C CHAWAN	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103, 177, 215, 154, 165, 100, 164, 282, 154, 151,174,177,203,238,291,289,174,242,241,199,	11/9/08	SCC
714	701	"	"
345	419,468,441,471,E13.005,E13.014,E13.015,E13.016, E13.018, E13.019,E13.025,E13.061, E13.062,E13.071	"	"
375	E7.081	"	"
295	21, 44, 11, 15	"	"
250	559.23	"	"
700	187	"	"
382	151, 203,219	6/20/09	SCC
345	441	6/20/09	SCC
ABOVE SEARCH-UPDATE		6/20/09	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DA TA BASE, SEE THE SEARCH HISTORY.	11/9/08	SCC
SEARCH INVENTOR NAME	"	"
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY	6/20/09	SCC
382/103,177,215,154,165,100,164,282,154,151,174,177,203,238,291,289 ,174,242,241,199".CCLS. US-PATENT TEXT SEARCH ONLY.	6/20/09	SCC
345/419,468,441,E13.005,E13.014,E13.015,E13.016.CCLS. TEXT SEARCH ONLY.	6/20/09	SCC
714/701.CCLS. TEXT SEARCH ONLY.	6/20/09	SCC
700/187.CCLS. " "	6/20/09	SCC
INTERFERENCE SEARCH.	6/20/09	SCC
345/E7.081 ABOLISH	6/20/09	SCC
SEARCH IEEE OR INSPEC DATA BASE.	6/20/09	SCC
SEARCH UP-DATE.	6/20/09	SCC

INTERFERENCE SEARCH

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Class	Subclass	Date	Examiner
382	151,203,219	6/20/09	SCC
345	441	6/20/09	SCC

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